

• 7.0 A, 30 V. $R_{DS(ON)}$ = 0.03 Ω @ V_{GS} = 10 V.

surface mount package.

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High density cell design for extremely low R_{DS(ON)}.

High power and current handling capability in a widely used



February 1997

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NDS9410S Single N-Channel Enhancement Mode Field Effect Transistor

Features

General Description

SO-8 N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as notebook computer power management and other battery powered circuits where fast switching, low in-line power loss, and resistance to transients are needed.

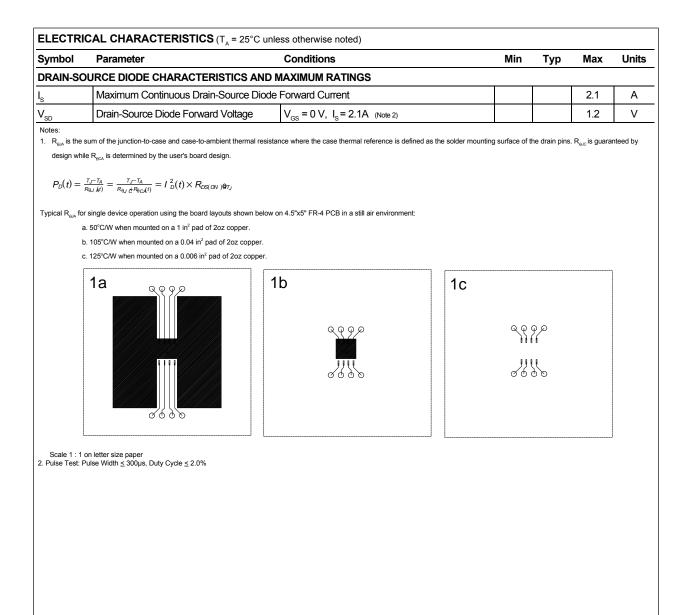
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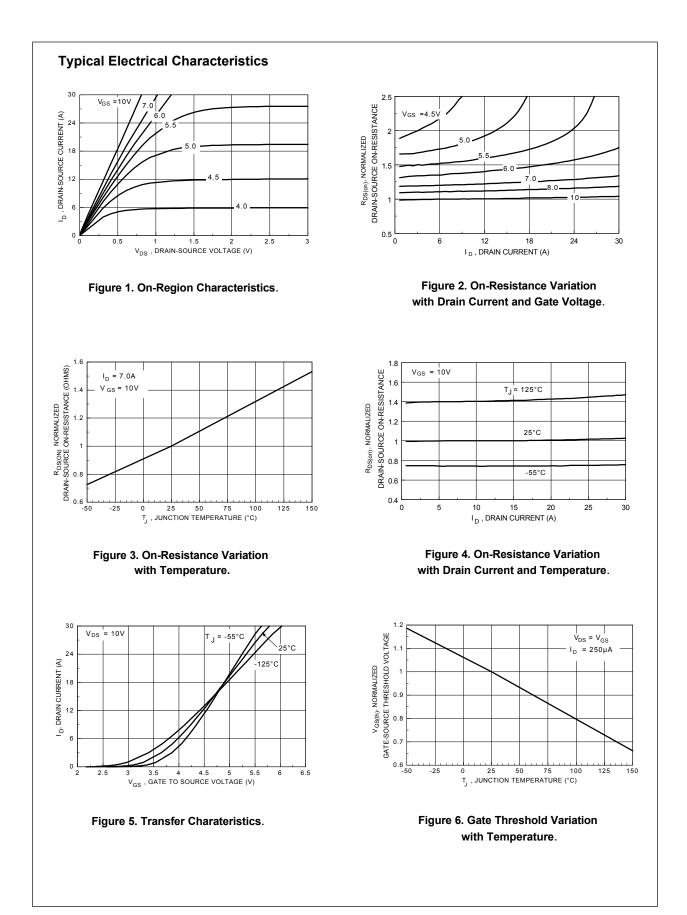
ABSOLI	JTE MAXIMUM RATINGS T _A = 25°C unles		ted	
Symbol	Parameter		NDS9410S	Units
V _{DSS}	Drain-Source Voltage		30 30 25	V
V _{GSS}	Gate-Source Voltage		±20	V
I _D	Drain Current - Continuous	(Note 1a)	7	А
	- Pulsed		25	
P _D	Maximum Power Dissipation	(Note 1a)	2.5	W
	WW.0250	(Note 1b)	1.2	
	A STATE WAY	(Note 1c)	1	
T_,T _{STG}	Operating and Storage Temperature Range		-55 to 150	°C
THERMA	L CHARACTERISTICS			
R _{ØJA}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	50	°C/W
Roic	Thermal Resistance, Junction-to-Case	(Note 1)	25	°C/W

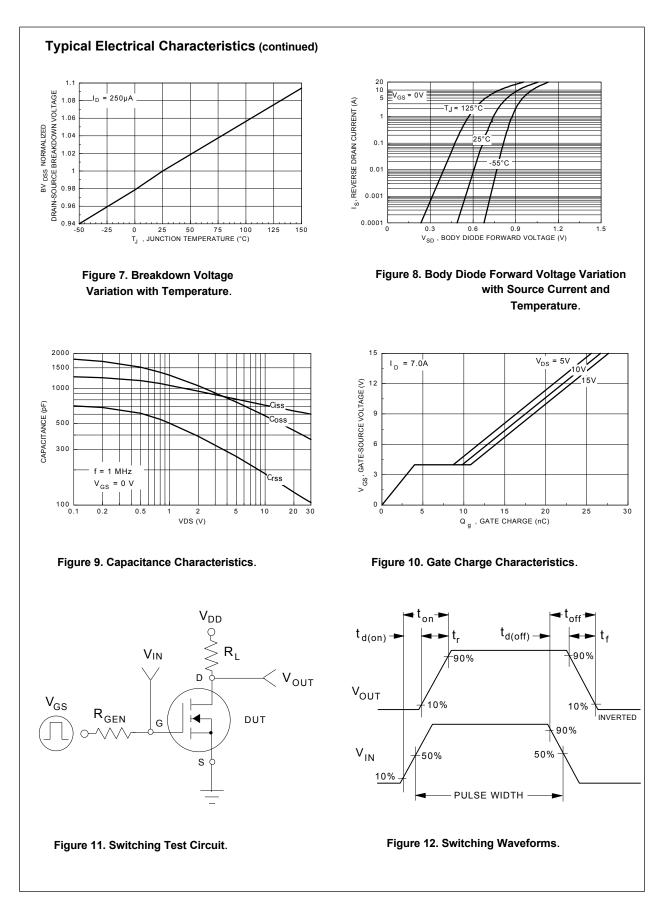
R_{ejc}

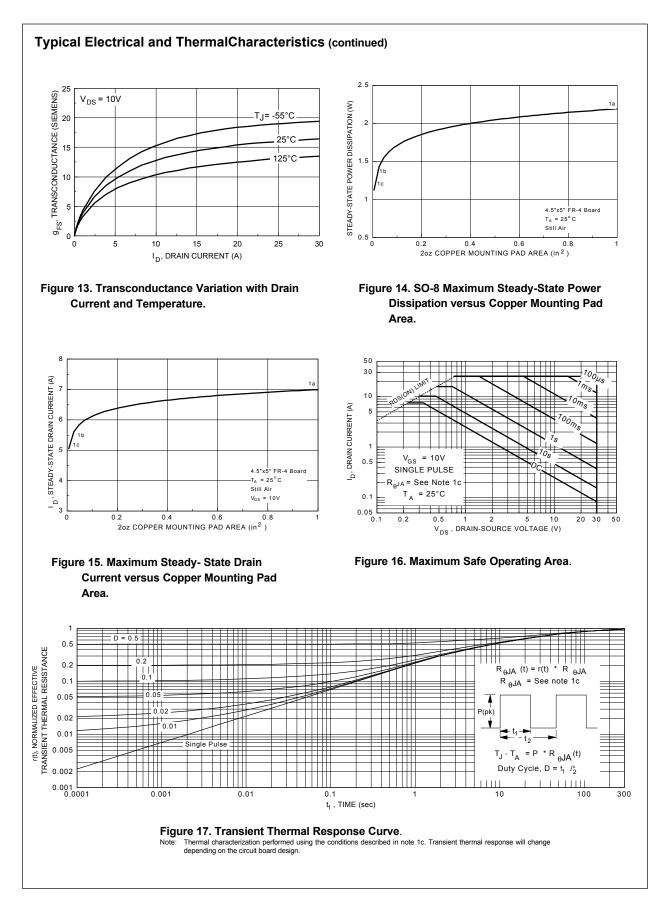
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Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	RACTERISTICS	·		•		•	•
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA		30			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V				1	μA
			T_= 55°C			10	μA
GSSF	Gate - Body Leakage, Forward	V _{GS} = 20 V, V _{DS} = 0 V	·			100	nA
	Gate - Body Leakage, Reverse	V _{GS} = -20 V, V _{DS} = 0 V				-100	nA
ON CHAR	ACTERISTICS (Note 2)	·					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		2	2.2	4	V
			T _J = 125°C	1.4	1.6	2.8	
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 7 \text{ A}$			0.026	0.03	Ω
			T _J = 125°C		0.036	0.055	
D(on)	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 5 \text{ V}$		25			
9 _{FS}	Forward Transconductance	$V_{\rm DS}$ = 10 V, $I_{\rm D}$ = 7 A			11		S
DYNAMIC	CHARACTERISTICS						
C _{iss}	Input Capacitance	V _{DS} = 15 V, V _{GS} = 0 V, f = 1.0 MHz			670		pF
C _{oss}	Output Capacitance				490		pF
C _{rss}	Reverse Transfer Capacitance				150		pF
SWITCHIN	IG CHARACTERISTICS (Note 2)					-	
t _{D(on)}	Tum - On Delay Time	$V_{DD} = 10 \text{ V}, \text{ I}_{D} = 1 \text{ A},$ $V_{GEN} = 10 \text{ V}, \text{ R}_{GEN} = 6 \Omega$			10	20	ns
ţ,	Turn - On Rise Time				15	30	ns
t _{D(off)}	Turn - Off Delay Time				19	40	ns
ţ	Turn - Off Fall Time				12	25	ns
Q _g	Total Gate Charge	$V_{DS} = 10 V,$ $I_{D} = 7 A, V_{GS} = 10 V$			18	25	nC
Q _{gs}	Gate-Source Charge	$I_{\rm D} = 7 \text{A}, V_{\rm GS} = 10 \text{V}$			4		nC
Q_{gd}	Gate-Drain Charge				6		nC

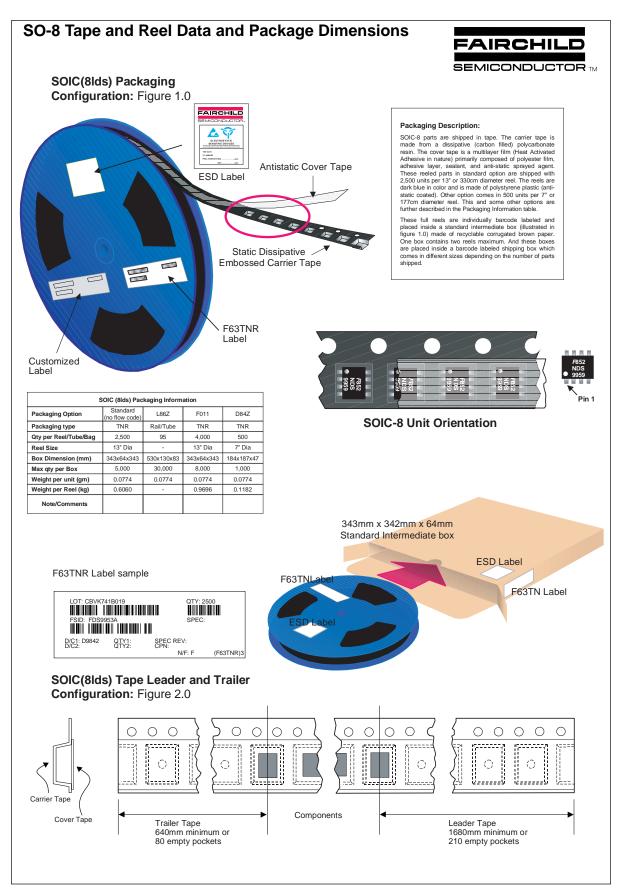


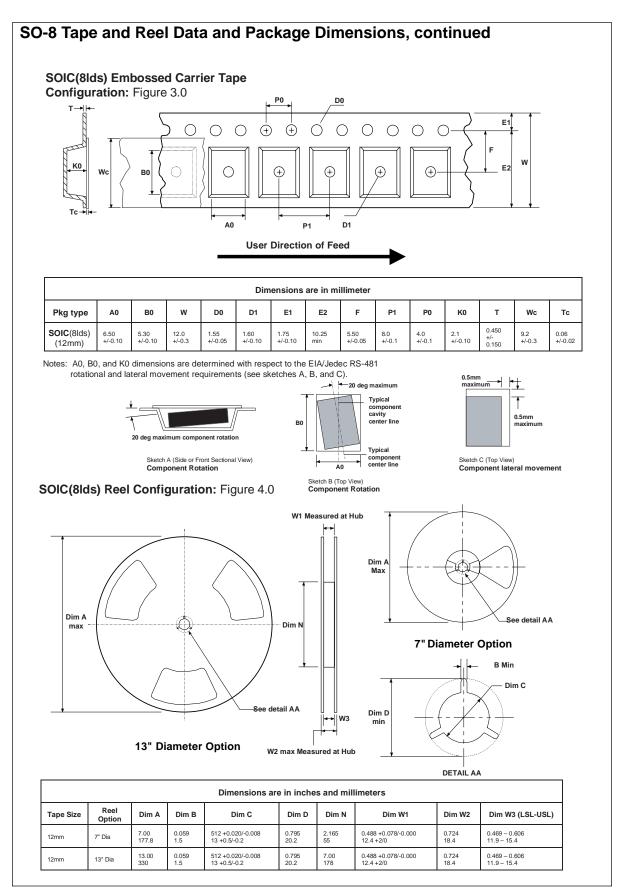


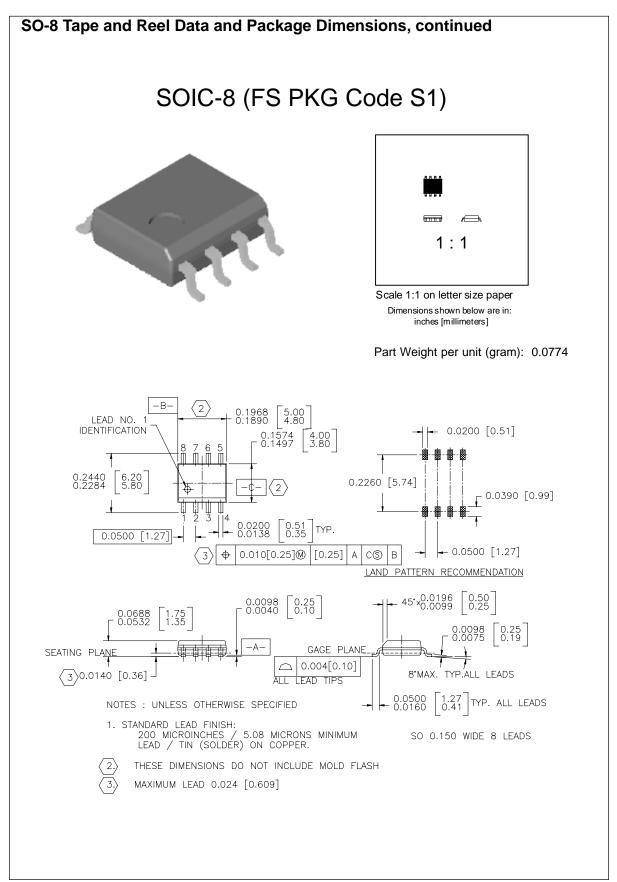




NDS9410S Rev.B







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